Search Notes



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Applicant(s)/Patent Under Reexamination

DUFT ET AL.

Examiner
S. Devi, Ph.D.

Art Unit

	SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Consultations with tQAS Witz & Wax. SPE Eyler & Stucker.	April, 08	SD
Appeal conference - Conferess SPE Jeff Stucker & SPE Mondesi	October, 08	SD

	INTERFERENCE SEA	RCH	
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